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## M.Tech. Degree Examination, Dec.2013/Jan.2014

**Design of VLSI Systems** 

Mme: 3 hrs.

Note: Answer any FIVE full questions.

Explain the terms modularity and locality with one example for each.

Explain: i) Full-custom mask design.

ii) Standard cell design.

(10 Marks)

2 Explain logic optimization with a typical flow diagram. (10 Marks)

Explain the wing design capture tools with tool names:

i) HDL design of ii) Schematic design

(10 Marks)

With necessary diagraphs, explain the simple Manchester adder with carry bypass. (10 Marks) 3

Draw the table for radified booth encoding values and design booth encoder and booth selector for this. (10 Marks)

State some commonly used shifters. Explain array funnel shifter with a neat diagram. 4

(10 Marks)

Explain bit-serial and bit-parallel adders.

(10 Marks)

Explain FSM design procedure with an example

(10 Marks)

Explain PLA control implementation with an example.

(10 Marks)

Explain the properties of **100** subsystems, and explain the basic I/O pad circuits. (10 Marks)

Explain: i) NRE costs

ii) Fixed costs.

(10 Marks)

Explain IEEE 1149 boundary scan architecture in detail.

(10 Marks)

Explain the terms controllability, observability and fault coverage. Explain 2 different fault 70737.y models. (10 Marks)

8 Writeshort notes on:

a. Ad-hoc testing.

b. ¿Design of RISC microcontroller.

c. Power distribution employed while designing special purpose subsystems.

d. Content addressable memory (CAM).

(20 Marks)